

What is claimed is:

1. A method of processing a semiconductor wafer having a plurality of epitaxial layers, including a P-side cladding layer adjacent to a waveguide layer, so as to create
5 a distributed Bragg reflecting (DBR) grating in a defined window area without creating a distributed feedback (DFB) grating over the remainder of the wafer, comprising the steps of:
 - depositing a protective layer over said wafer;
 - removing said protective layer over a portion of said cladding layer to define a
10 window in an area of said wafer having negligible optical gain;
 - applying a photoresist over said wafer including said window area;
 - exposing said entire photoresist to interfering laser beams to create a grating pattern in said photoresist;
 - transferring said grating pattern into said cladding layer at said window area;
 - 15 and
 - removing the remainder of said protective coating prior to depositing additional layers of said wafer
2. The method of claim 1 wherein said protective layer is selected from the group
20 consisting of SiO₂, Si₃N₄ and a metal.
3. The method of claim 1 wherein said photoresist is removed prior to transferring said grating pattern into said cladding layer.
- 25 4. The method of claim 3 wherein a photoresist is exposed to said interfering laser holography beams provided from an argon laser.
5. The method of claim 4 wherein argon laser is operated at a wavelength of 458 nm.

30

6. The method of claim 5 wherein after said photoresist is removed using an etchant selected from the group consisting of SF_6 , CCl_2F_2 , CClF_3 and CF_4 .
7. The method of claim 6 wherein after said photoresist is removed, a wet etchant selected from the group consisting of SiCl_4 or BCl_3 is used to transfer said pattern into said cladding layer.
8. The method of claim 1 wherein said protective layer has a refractive index - different than the refractive index of said photoresist to cancel said interfering laser beams over said protective layer.
9. The method of claim 1 wherein said additional layers include gain layers beyond said window area.
10. The method of claim 1 wherein said additional layers include non-gain layers over said window area.